PLUS173-10

DESCRIPTION

The PLUS173–10 PLD is a high speed, combinatorial Programmable Logic Array. The Philips Semiconductors state-of-the-art Oxide Isolated Bipolar fabrication process is employed to produce maximum propagation delays of 10ns or less.

The 24-pin PLUS173–10 device has a programmable AND array and a programmable OR array. Unlike PAL® devices, 100% product term sharing is supported. Any of the 32 logic product terms can be connected to any or all of the 10 output OR gates. Most PAL ICs are limited to 7 AND terms per OR function; the PLUS173–10 device can support up to 32 input wide OR functions.

The polarity of each output is userprogrammable as either Active-High or Active-Low, thus allowing AND-OR or AND-NOR logic implementation. This feature adds an element of design flexibility, particularly when implementing complex decoding functions.

The PLUS173–10 device is userprogrammable using one of several commercially available, industry standard PLD programmers.

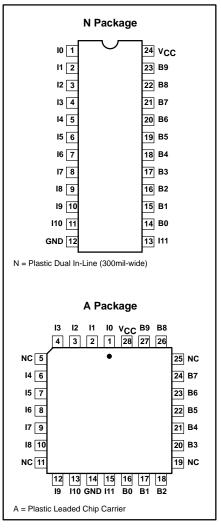
FEATURES

- I/O propagation delays
 - 10ns (worst case)
- Functional superset of 20L10 and most other 24-pin combinatorial PAL devices
- Two programmable arrays
 - Supports 32 input wide OR functions
- 12 inputs
- 10 bi-directional I/O
- 42 AND gates
 - 32 logic product terms
 - 10 direction control terms
- Programmable output polarity
 - Active-High or Active-Low
- Security fuse
- 3-State outputs
- Power dissipation: 850mW (typ.)
- TTL Compatible

APPLICATIONS

- Random logic
- Code converters
- Fault detectors
- Function generators
- Address mapping
- Multiplexing

PIN CONFIGURATIONS



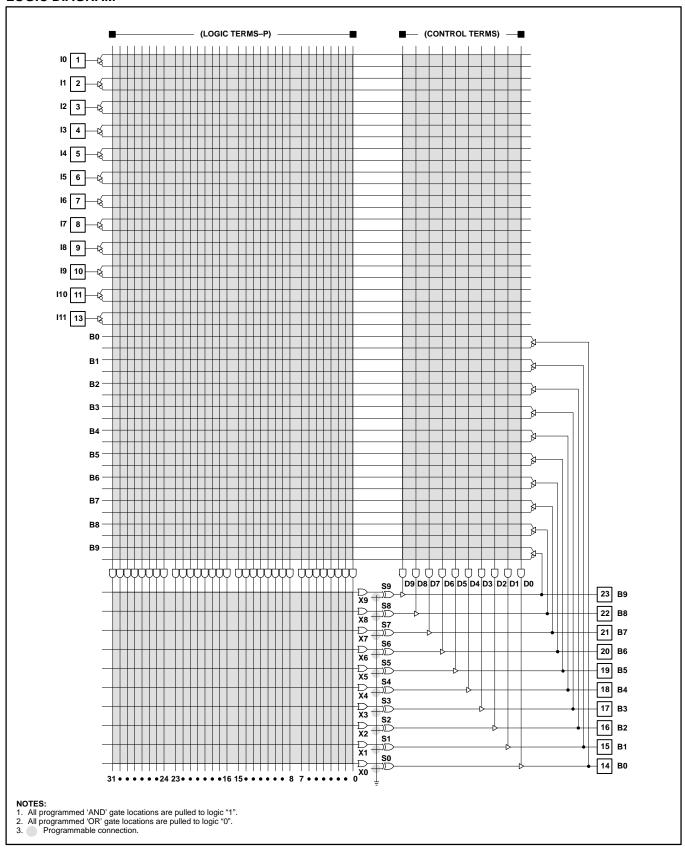
ORDERING INFORMATION

DESCRIPTION	t _{PD} (MAX)	ORDER CODE	DRAWING NUMBER
24-Pin Plastic Dual In-Line 300mil-wide	10ns	PLUS173-10N	0410D
28-Pin Plastic Leaded Chip Carrier	10ns	PLUS173-10A	0401F

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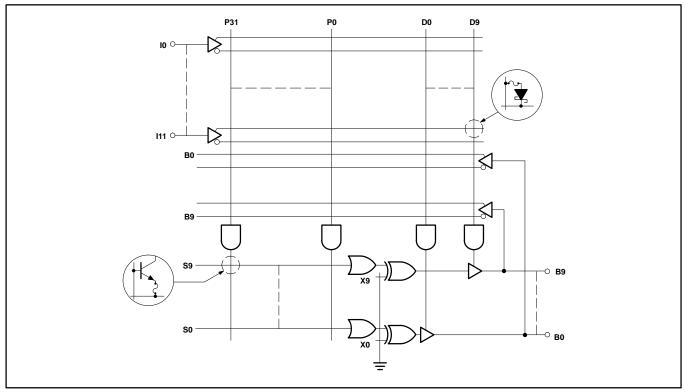
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LOGIC DIAGRAM



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FUNCTIONAL DIAGRAM



ABSOLUTE MAXIMUM RATINGS¹

		RATING		
SYMBOL	PARAMETER	Min	Max	UNIT
V _{CC}	Supply voltage		+7	V _{DC}
V _{IN}	Input voltage		+5.5	V_{DC}
V _{OUT}	Output voltage		+5.5	V_{DC}
I _{IN}	Input currents	-30	+30	mA
I _{OUT}	Output currents		+100.0	mA
T _{amb}	Operating free-air temperature range	0	+75	°C
T _{stg}	Storage temperature range	- 65	+150	°C

THERMAL RATINGS

TEMPERATURE				
Maximum junction	150°C			
Maximum ambient	75°C			
Allowable thermal rise ambient to junction	75°C			

NOTES:

Stresses above those listed may cause malfunction or permanent damage to the device. This
is a stress rating only. Functional operation at these or any other condition above those
indicated in the operational and programming specification of the device is not implied.

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DC ELECTRICAL CHARACTERISTICS

 $0^{\circ}C \leq T_{amb} \leq +75^{\circ}C,~4.75 \leq V_{CC} \leq 5.25V$

	PARAMETER	TEST CONDITIONS		LIMITS		
SYMBOL			MIN	TYP ¹	MAX	UNIT
Input volt	age ²	•				
V _{IL}	Low	V _{CC} = MIN			0.8	V
V_{IH}	High	V _{CC} = MAX	2.0			V
V_{IC}	Clamp	$V_{CC} = MIN, I_{IN} = -12mA$		-0.8	-1.2	V
Output vo	Itage ²	•				
		V _{CC} = MIN				
V_{OL}	Low ⁴	I _{OL} = 15mA		0.4	0.5	V
V_{OH}	High ⁵	I _{OH} = -2mA	2.4	2.9		V
Input curr	ent ⁹	•				
		V _{CC} = MAX				
I _{IL}	Low	V _{IN} = 0.45V		-20	-100	μΑ
I _{IH}	High	$V_{IN} = V_{CC}$		1	40	μΑ
Output cu	rrent	•				
		V _{CC} = MAX				
$I_{O(OFF)}$	Hi-Z state ⁸	V _{OUT} = 2.7V		0	80	μΑ
		V _{OUT} = 0.45V		-15	-140	
I _{OS}	Short circuit ^{3, 5, 6}	V _{OUT} = 0V	-15	-30	-70	mA
I _{CC}	V _{CC} supply current ⁷	V _{CC} = MAX		170	210	mA
Capacitan	се					
_		V _{CC} = 5V				
I _{IN}	Input	V _{IN} = 2.0V		8		pF
C_{B}	1/0	V _B = 2.0V		15		pF

- 1. All typical values are at V_{CC} = 5V, T_{amb} = +25°C. 2. All voltage values are with respect to network ground terminal.
- 3. Test one at a time.
- 4. Measured with inputs 10 14 = 0V, inputs 15 19 = 4.5V, 111 = 4.5V and 110 = 10V. For outputs 10 14 = 10V, inputs 10 14 = 10V, inputs 10 14 = 10V, inputs 10 14 = 10V. same conditions except I11 = 0V.
- 5. Same conditions as Note 4 except input I11 = +10V.
- 6. Duration of short circuit should not exceed 1 second.
 7. I_{CC} is measured with inputs I0 I11 and B0 B9 = 0V. Part in Virgin State.
- 8. Leakage values are a combination of input and output leakage.
- 9. I_{IL} and I_{IH} limits are for dedicated inputs only (I0 I11).

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AC ELECTRICAL CHARACTERISTICS

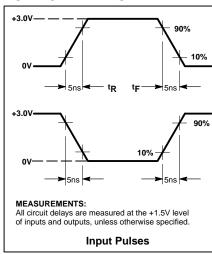
 $0^{\circ}C \le T_{amb} \le +75^{\circ}C, \ 4.75 \le V_{CC} \le 5.25V, \ R_1 = 300\Omega, \ R_2 = 390\Omega$

				TEST	LIMITS			
SYMBOL	PARAMETER	FROM	то	CONDITION	MIN	TYP	MAX	UNIT
t _{PD}	Propagation Delay ²	Input +/-	Output +/-	C _L = 30pF		8	10	ns
t _{OE}	Output Enable ¹	Input +/-	Output –	C _L = 30pF		8	10	ns
t _{OD}	Output Disable ¹	Input +/-	Output +	$C_L = 5pF$		8	10	ns

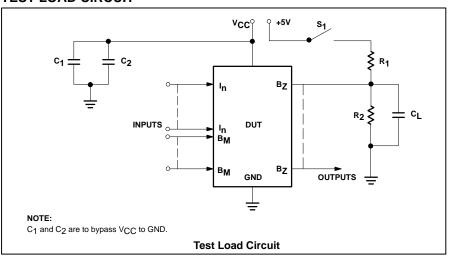
NOTES:

- 1. For 3-State outputs; output enable times are tested with $C_L = 30 pF$ to the 1.5V level, and S_1 is open for high-impedance to High tests and closed for high-impedance to Low tests. Output disable times are tested with $C_L = 5 pF$. High-to-High impedance tests are made to an output voltage of $V_T = (V_{OH} - 0.5V)$ with S_1 open, and Low-to-High impedance tests are made to the $V_T = (V_{OL} + 0.5V)$ level with S_1 closed. 2. All propagation delays are measured and specified under worst case conditions.

VOLTAGE WAVEFORM



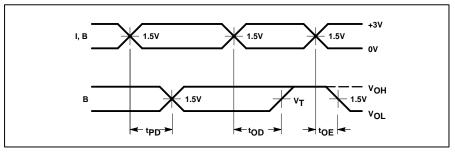
TEST LOAD CIRCUIT



TIMING DEFINITIONS

SYMBOL	PARAMETER
t _{PD}	Propagation delay between input and output.
t _{OD}	Delay between input change and when output is off (Hi-Z or High).
t _{OE}	Delay between input change and when output reflects specified output level.

TIMING DIAGRAM



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LOGIC PROGRAMMING

The PLUS173–10 is fully supported by industry standard (JEDEC compatible) PLD CAD tools, including Philips Semiconductors SNAP design software package. ABEL™ and CUPL™ design software packages also support the PLUS173–10 architecture.

All packages allow Boolean and state equation entry formats. SNAP, ABEL and CUPL also accept, as input, schematic capture format.

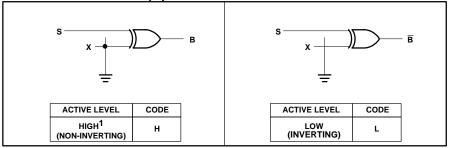
PLUS173–10 logic designs can also be generated using the program table entry format, which is detailed on the following page. This program table entry format is supported by SNAP only.

To implement the desired logic functions, the state of each logic variable from logic equations (I, B, O, P, etc.) is assigned a symbol. The symbols for TRUE, COMPLEMENT, INACTIVE, PRESET, etc., are defined below.

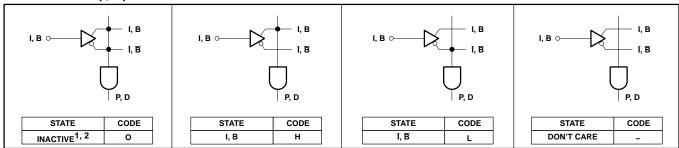
PROGRAMMING AND SOFTWARE SUPPORT

Refer to Section 9 (Development Software) and Section 10 (Third-party Programmer/ Software Support) of this data handbook for additional information.

OUTPUT POLARITY - (B)

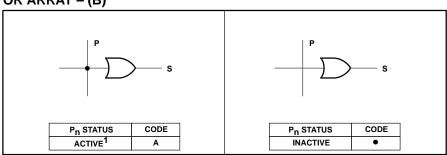


AND ARRAY - (I, B)



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OR ARRAY - (B)



NOTES:

- This is the initial unprogrammed state of all link pairs. It is normally associated with all unused (inactive) AND gates P_n, D_n.
- Any gate P_n, D_n will be unconditionally inhibited if both the true and complement of any input (I, B) are left intact.

VIRGIN STATE

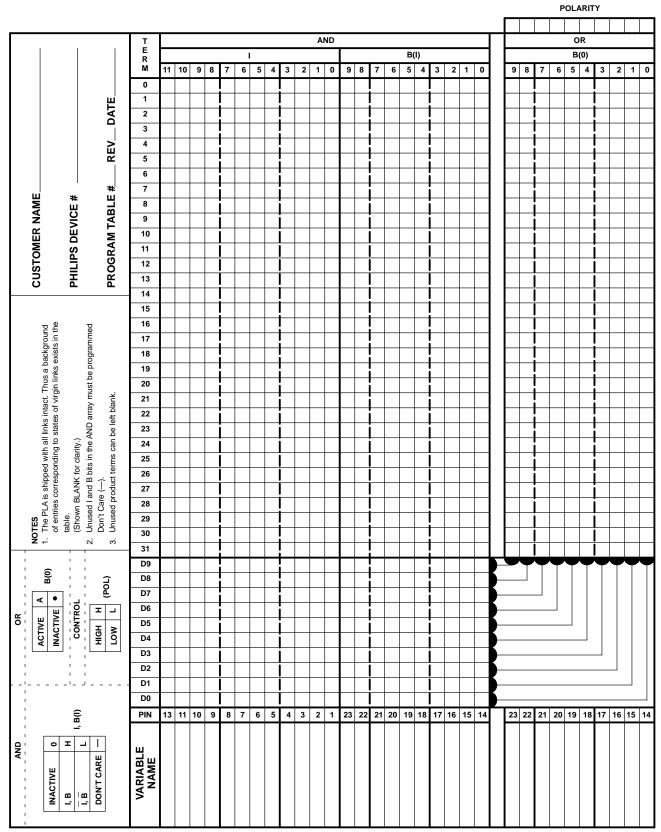
A factory shipped virgin device contains all fusible links intact, such that:

- All outputs are at "H" polarity.
- 2. All P_n terms are disabled.
- 3. All P_n terms are active on all outputs.

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PLA PROGRAM TABLE



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SNAP RESOURCE SUMMARY DESIGNATIONS

